

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/767,768	<b>Applicant(s)/Patent under Reexamination</b> OGAWA, HIDEHIKO
	<b>Examiner</b> Thomas D. Lee	<b>Art Unit</b> 2624

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner